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| INFORMATION DISCLOSURE CITATION (Use several sheets if necessary) | Docket Number (Optional) COHL-5410 | Application Number 10/065,262 |
| | Applicant(s) Michael J. Scaggs | |
| | Filing Date September 30, 2002 | Group Art Unit 1763 |

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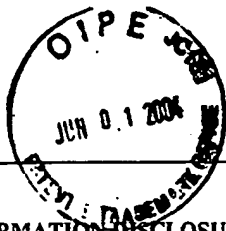
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| Examiner R. B. B. B. | Date Considered 7-2005 |
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INFORMATION DISCLOSURE CITATION
(Use several sheets if necessary)

Docket Number (Optional)
COHL-5410

Application Number
10/065,262

Applicant(s)
Michael J. Scaggs

Filing Date
09/30/2002

Group Art Unit
Unknown

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| Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. | |

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| INFORMATION DISCLOSURE CITATION (Use separate sheets if necessary) | Docket Number (Optional) COHL-5410 | Application Number 10/065,262 |
| | Applicant(s) Michael J. Scaggs | |
| | Filing Date 09/30/2002 | Group Art Unit Unknown |

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Complete if Known

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| Application Number | 10/065,262 |
| Filing Date | 09/30/2002 |
| First Named Inventor | Michael J. Scaggs |
| Group Art Unit | 1763 |
| Examiner Name | Mills, Gregory L. |
| Attorney Docket Number | 1443.01 |

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K. Burch

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